MAGOO2AG"供应商

Preferred Device

Self-Protected FET with Temperature and Current Limit

65 V, 6.5 A, Single N–Channel, DPAK

HDPlus[™] devices are an advanced series of power MOSFETs which utilize ON Semiconductor's latest MOSFET technology process to achieve the lowest possible on–resistance per silicon area while incorporating smart features. Integrated thermal and current limits work together to provide short circuit protection. The devices feature an integrated Drain–to–Gate Clamp that enables them to withstand high energy in the avalanche mode. The Clamp also provides additional safety margin against unexpected voltage transients. Electrostatic Discharge (ESD) protection is provided by an integrated Gate–to–Source Clamp.

Features

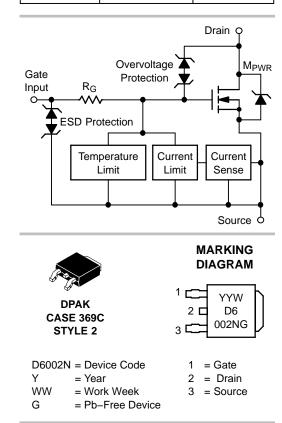
- Short Circuit Protection/Current Limit
- Thermal Shutdown with Automatic Restart
- I_{DSS} Specified at Elevated Temperature
- Avalanche Energy Specified
- Slew Rate Control for Low Noise Switching
- Overvoltage Clamped Protection
- Pb–Free Package is Available



ON Semiconductor®

http://onsemi.com

V _{DSS} (Clamped)	R _{DS(on)} TYP	I _D TYP (Limited)
65 V	210 m Ω	6.5 A



ORDERING INFORMATION

Device	Package	Shipping [†]
NID6002NT4	DPAK	2500/Tape & Reel
NID6002NT4G	DPAK (Pb–Free)	2500/Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Preferred devices are recommended choices for future use and best overall value.

MOSPET IMAXIMUMTRATING STORE 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage Internally Clamped	V _{DSS}	70	Vdc
Gate-to-Source Voltage	V _{GS}	±14	Vdc
Drain Current Continuo	us I _D	Internally Limited	
Total Power Dissipation @ $T_A = 25^{\circ}C$ (Note 1) @ $T_A = 25^{\circ}C$ (Note 2)	PD	1.3 2.5	W
Thermal Resistance Junction-to-Case Junction-to-Ambient (Note 1) Junction-to-Ambient (Note 2)	R _{θJC} R _{θJA} R _{θJA}	3.0 95 50	°C/W
Single Pulse Drain–to–Source Avalanche Energy (V_{DD} = 50 Vdc, V_{GS} = 5.0 Vdc, I_L = 1.3 Apk, L = 160 mH, R_G = 25 Ω)	E _{AS}	143	mJ
Operating and Storage Temperature Range (Note 3)	T _J , T _{stg}	-55 to 150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected. 1. Surface mounted onto minimum pad size (100 sq/mm) FR4 PCB, 1 oz cu.

Mounted onto 1" square pad size (700 sq/mm) FR4 PCB, 1 oz cu.
Normal pre-fault operating range. See thermal limit range conditions.

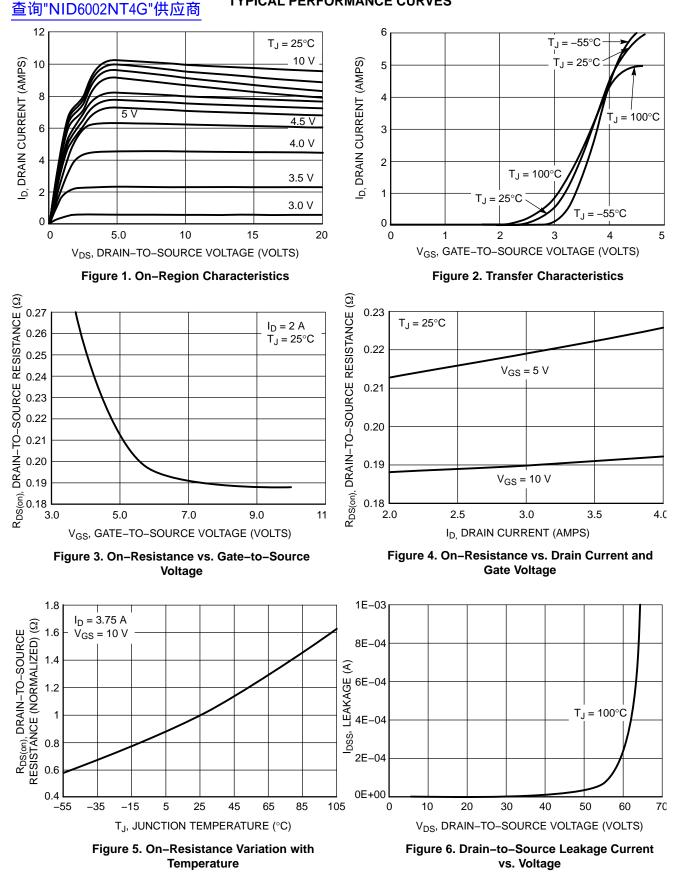
世段新年時下時時時代了時時時代本時TERISTICS (T_J = 25°C unless otherwise noted)

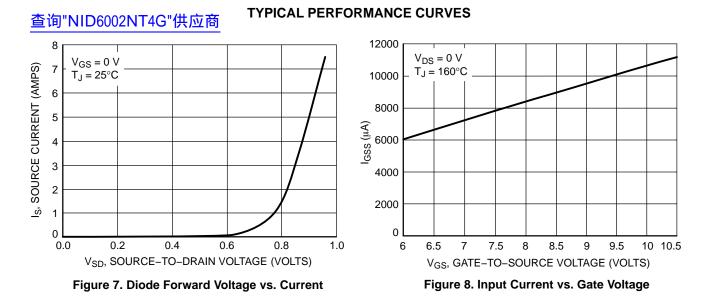
	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS						
Drain-to-Source Clamped Breakdown Voltage ($V_{GS} = 0 \text{ V}, I_D = 2 \text{ mA}$)			60	65	70	V
Zero Gate Voltage Drain Current $(V_{DS} = 52 \text{ V}, V_{GS} = 0 \text{ V})$			_	27	100	μΑ
Gate Input Current ($V_{GS} = 5.0 \text{ V}, V_{DS} = 0 \text{ V}$)			_	45	200	μΑ
ON CHARACTERISTICS						
Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 150 \ \mu A$) Threshold Temperature Coefficient			1.0 -	1.85 5.0	2.4	V –mV/°C
Static Drain-to-Source On-Resistance (Note 4) $(V_{GS} = 10 \text{ V}, I_D = 2.0 \text{ A}, T_J @ 25^{\circ}\text{C})$			_	185	210	mΩ
Static Drain-to-Source On-Re (V_{GS} = 5.0 V, I_D = 2.0 A, T_J @ 2 (V_{GS} = 5.0 V, I_D = 2.0 A, T_J @ 2 (V_{GS} = 5.0 V, I_D = 2.0 A, T_J @ 2 (V_{GS} = 5.0 V, I_D = 2.0 A)	R _{DS(on)}		210 445	240 520	mΩ	
Source–Drain Forward On Volta $(I_S = 7.0 \text{ A}, V_{GS} = 0 \text{ V})$	V _{SD}	-	0.9	1.1	V	
SWITCHING CHARACTERIST	ICS					
Turn-on Delay Time	$ \begin{array}{l} {\sf R}_{\sf L} = 6.6 \ \Omega, \ {\sf V}_{in} = \ 0 \ \text{to} \ 10 \ {\sf V}, \\ {\sf V}_{\sf DD} = 13.8 \ {\sf V}, \ {\sf I}_{\sf D} = 2.0 \ {\sf A}, \ 10\% \ {\sf V}_{in} \ \text{to} \ 10\% \ {\sf I}_{\sf D} \end{array} $	td _(on)	-	103	120	ns
Turn-on Rise Time		t _{rise}	-	246	285	ns
Turn-off Delay Time	$\begin{array}{l} {\sf R}_{\sf L} = 6.6 \; \Omega, \; {\sf V}_{in} = \; 0 \; \text{to} \; 10 \; {\sf V}, \\ {\sf V}_{\sf DD} = 13.8 \; {\sf V}, \; {\sf I}_{\sf D} = 2.0 \; {\sf A}, \; 90\% \; {\sf V}_{in} \; \text{to} \; 90\% \; {\sf I}_{\sf D} \end{array}$	td _(off)	-	742	850	ns
Turn–off Fall Time	$\begin{array}{l} {\sf R}_{\sf L} = 6.6 \; \Omega, \; {\sf V}_{in} = 0 \; \text{to} \; 10 \; {\sf V}, \\ {\sf V}_{\sf DD} = 13.8 \; {\sf V}, \; {\sf I}_{\sf D} = 2.0 \; {\sf A}, \; 90\% \; {\sf I}_{\sf D} \; \text{to} \; 10\% \; {\sf I}_{\sf D} \end{array}$	t _{fall}	-	707	780	ns
Slew Rate ON	$\begin{array}{l} {\sf R}_{\sf L} = 6.6 \ \Omega, \ {\sf V}_{in} = \ 0 \ \text{to} \ 10 \ {\sf V}, \\ {\sf V}_{\sf DD} = 13.8 \ {\sf V}, \ {\sf I}_{\sf D} = 2.0 \ {\sf A}, \ 70\% \ \text{to} \ 50\% \ {\sf V}_{\sf DD} \end{array}$	dV _{DS} /dT _{on}	-	73	-	V/μs
Slew Rate OFF	R_L = 6.6 Ω, V_{in} = 0 to 10 V, V_{DD} = 13.8 V, I_D = 2.0 A, 50% to 70% V_{DD}	dV _{DS} /dT _{off}	_	35	-	V/µs
SELF PROTECTION CHARAC	TERISTICS (T _J = 25° C unless otherwise noted) (N	ote 5)				
Current Limit		I _{LIM}	4.0 4.0 -	6.4 5.5 7.9	11 11 -	A
Temperature Limit (Turn-off)	V _{GS} = 5.0 V	T _{LIM(off)}	150	180	200	°C
Thermal Hysteresis	V _{GS} = 5.0 V	$\Delta T_{LIM(on)}$	-	10	-	°C
emperature Limit (Turn-off) V _{GS} = 10 V		T _{LIM(off)}	150	180	200	°C
Thermal Hysteresis	V _{GS} = 10 V	$\Delta T_{LIM(on)}$	-	20	-	°C
$ \begin{array}{ll} \mbox{Input Current during} & V_{DS} = 0 \ V, \ V_{GS} = 5.0 \ V, \ T_J = T_J > T_{(fault)} \\ \ V_{DS} = 0 \ V, \ V_{GS} = 10 \ V, \ T_J = T_J > T_{(fault)} \\ \end{array} $		I _{g(fault)}	5.5 12	5.2 11	_	mA
SD ELECTRICAL CHARACTE	ERISTICS (T _J = 25° C unless otherwise noted)					
Electro Static Discharge Capa		ESD		1		V

Electro-Static Discharge Capability	ESD				V
Human Body Model (HBM)		8000	-	-	
Machine Model (MM)		400	-	-	

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
Fault conditions are viewed as beyond the normal operating range of the part.
Current limit measured at 380 μs after gate pulse.

TYPICAL PERFORMANCE CURVES





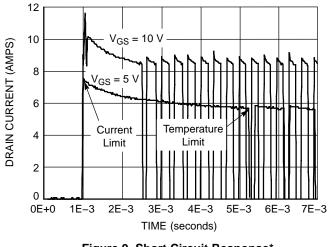
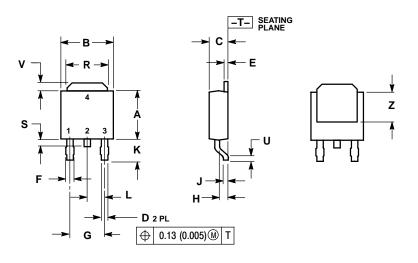


Figure 9. Short Circuit Response*

*(Actual thermal cycling response in short circuit dependent on device power level, thermal mounting, and ambient temperature conditions)

查询"NID6002NT4G"供应商

DPAK CASE 369C-01 ISSUE O



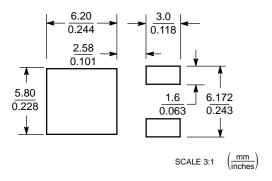
	INCHES		MILLIN	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.22
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.180	BSC	4.58	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
Κ	0.102	0.114	2.60	2.89
L	0.090 BSC		2.29 BSC	
R	0.180	0.215	4.57	5.45
S	0.025	0.040	0.63	1.01
U	0.020		0.51	
٧	0.035	0.050	0.89	1.27
Ζ	0.155		3.93	

STYLE 2: PIN 1. GATE 2. DRAIN

3. SOURCE

4. DRAIN

SOLDERING FOOTPRINT



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